III B.Tech I Semester Supplementary Examinations, April 2023 Digital Design Through Verilog
(ECE)

| Roll No |  |  |  |  |  |  |  |  |  |  |
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## Time: 3 hours

Max. Marks: 75
Note: This question paper contains two parts A and B
Part A is compulsory which carriers 25 marks and Answer all questions.
Part B Consists of 5 SECTIONS (One SECTION for each UNIT). Answer FIVE Questions, Choosing ONE Question from each SECTION and each Question carries 10 marks.

PART-A (25 Marks)

| 1). a | Define Verilog HDL. | [2M] |
| :---: | :---: | :---: |
| b | What is Module? | [3M] |
| c | What is AND gate primitive? | [2M] |
| d | Define strengths and content resolution. | [3M] |
| e | What is initial construct? | [2M] |
| f | Explain force-release construct. | [3M] |
| g | Explain tranif1 and tranif0. | [2M] |
| h | Define module path. | [3M] |
| i | What is capacitive model? | [2M] |
| j | Explain about Testbench? | [3M] |

## PART-B (50 MARKS)

SECTION-I
2 a) Differentiate between synthesis and simulation.
b) Explain levels of abstraction in digital design with examples.

3 Explain the following:
a) Programming Language interface
b) Functional verification

## SECTION-II

4 a) Explain continuous assignments and strengths with example
b) Explain delays with continuous assignments

5 a) Write short notes on Tri state gates and delays associated with them. [5M]
b) Write Verilog code and test bench of 4 to 1 multiplexer using ternary operator.

## SECTION-III

6 a) Write Verilog description of JK flip flop with preset and clear facility.
b) Differentiate between blocking and nonblocking assignments with examples.

OR
7 Write Verilog code to model ALU and write the test bench for the same. [10M]

## SECTION-IV

8 Explain in detail about Basic switch primitives and resistive switches. [10M] OR
9 Design a half adder module with time delay assignment through parameter [10M] declaration and write the test bench for the same.

SECTION-V
10 Write short notes on sequential models.
OR
11 Differentiate between combinational circuits testing and sequential circuits [10M] testing.
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